## Notice of References Cited Application/Control No. 10/825,670 Examiner Chuong A. Luu Applicant(s)/Patent Under Reexamination SHIN ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,515,356 B1	02-2003	Shin et al.	257/678
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
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	ı	US-			
	J	US-			
	К	US-			
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## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

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